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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant: Hong et al.			
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U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
/M7	5,422,571	Jun. 6, 1995	Gurney et al.	324	252	Feb. 8, 1993

FOREIGN PATENT DOCUMENTS							
Examiner Initial*	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
/M7	10-313138	Nov. 24, 1998	Japan			Abs.	
/	0 845 820	Jun. 3, 1998	Europe			X	
/	WO 00/63714	Oct. 26, 2000	WIPO			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
/M7	Egelhoff et al.; "Spectacular Electron Scattering in Metallic Thin Films"; <i>J. Vac. Sci. Technol.</i> B17(4), Jul/Aug 1999
/	de Vries et al.; "Oscillatory Interlayer Exchange Coupling with the Cu Cap Layer Thickness in Co/Cu/Co/Cu (100)"; <i>Phys. Rev. Lett.</i> Vol. 75, pp. 4306; 1995.
/	Ueno et al.; "Read-Write Performance of Spin-Filter-Spin-Valve Heads"; <i>IEEE Trans. on Magnetics</i> ; Vol. 36, No. 5; pp.2572-2574; Sep. 2000
/	Swagten et al.; "Enhanced Giant Magnetoresistance in Spin-Valves Sandwiched Between Insulating NiO"; <i>Physical Review</i> ; Vol. 53, No. 14, Part 2; pp. 9109-9114
/	Wang et al.; "Effect of Au Underlayers on GMR Properties of NiFe/Cu/CoFe Sandwiches"; <i>IEEE Trans. on Magnetics</i> ; Vol. 32, No. 5; pp.4728-4730; Sep. 1996

Examiner <i>Kui Peto</i>	Date Considered <i>7/7/04</i>
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[illegible][illegible]

Y. H. P.	Hong et al.; "Effect of Thin Oxide Capping on Interlayer Coupling in Spin Valves"; <i>IEEE Trans. on Magnetics</i> ; Vol. 36, No. 5; September 2000; pp. 2629-2631

John R. R.

7/7/04

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***This reference was previously submitted, but the copy of the reference might have been incomplete.**